

AMENDMENT TO THE SPECIFICATION

Paragraph beginning on page 1, line 30, has been amended as follows:

B1 In a test operation, data to be written into a memory cell is applied to memory 220 from tester 222 via input/output lines 24 and input/output pins 40. Also, an address signal and a control signal are applied to control circuit 234 via input lines 28, input pins 38, and input buffers 242. Data is written into the specified address in memory array 230. That data is read out and applied to tester 222 via input/output buffer 248, input/output pins 40 and input/output lines 24. Tester 222 determines the test result.